Alberto Herrera-Gomez

List of Publications by Year in descending order

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73 papers 1,775 citations

26 h-index

218662

302107 39 g-index

74 all docs

74 docs citations

74 times ranked 1893 citing authors

#	Article	lF	CITATIONS
1	Oxidation mechanism of metallic chromium at room temperature. Applied Surface Science, 2021, 542, 148636.	6.1	18
2	A discussion of approaches for fitting asymmetric signals in Xâ€ray photoelectron spectroscopy (XPS), noting the importance of Voigtâ€like peak shapes. Surface and Interface Analysis, 2021, 53, 689-707.	1.8	20
3	Introductory guide to backgrounds in XPS spectra and their impact on determining peak intensities. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2020, 38, .	2.1	62
4	Assessment of the frequency and nature of erroneous x-ray photoelectron spectroscopy analyses in the scientific literature. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2020, 38, .	2.1	105
5	Uncertainties in photoemission peak fitting accounting for the covariance with background parameters. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2020, 38, .	2.1	16
6	Proliferation of Faulty Materials Data Analysis in the Literature. Microscopy and Microanalysis, 2020, 26, 1-2.	0.4	59
7	A selfâ€consistent multipleâ€peak structure of the photoemission spectra of metallic Fe 2 <i>p</i> as a function of film thickness. Surface and Interface Analysis, 2020, 52, 591-599.	1.8	5
8	Versailles Project on Advanced Materials and Standards interlaboratory study on intensity calibration for x-ray photoelectron spectroscopy instruments using low-density polyethylene. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2020, 38, 063208.	2.1	21
9	Corrosion Resistant TiTaN and TiTaAlN Thin Films Grown by Hybrid HiPIMS/DCMS Using Synchronized Pulsed Substrate Bias with No External Substrate Heating. Coatings, 2019, 9, 841.	2.6	5
10	Intensity modulation of the Shirley background of the Cr $3 < i > p < /i >$ spectra with photon energies around the Cr $2 < i > p < /i >$ edge. Surface and Interface Analysis, 2018, 50, 246-252.	1.8	15
11	Response to the letter: Comment on "Intensity modulation of the Shirley background of the Cr 3 <i>p</i> spectra with photon energies around the Cr 2 <i>p</i> edge―by R. Bavand, L. Chen, R. França, et al. Surface and Interface Analysis, 2018, 50, 686-687.	1.8	0
12	Micro-tribological performance of fullerene-like carbon and carbon-nitride surfaces. Tribology International, 2018, 128, 104-112.	5.9	11
13	Laser Reflection as a Simple Prospect Tool for Nondestructive Quality Control of Charged Lapping Plates. Journal of Tribology, 2017, 139, .	1.9	O
14	Accurate modeling of gate tunneling currents in Metal-Insulator-Semiconductor capacitors based on ultra-thin atomic-layer deposited Al2O3 and post-metallization annealing. Thin Solid Films, 2017, 638, 48-56.	1.8	19
15	Facile obtaining of Iridium(0), Platinum(0) and Platinum(0)-Iridium(0) alloy nanoparticles and the catalytic reduction of 4-nitrophenol. Materials Chemistry and Physics, 2017, 201, 289-296.	4.0	12
16	Detailed peak fitting analysis of the Zn $2 < i > p < i > p $ photoemission spectrum for metallic films and its initial oxidation stages. Surface and Interface Analysis, 2017, 49, 1078-1087.	1.8	35
17	Composition assessment of ferric oxide by accurate peak fitting of the Fe 2 <i>p</i> photoemission spectrum. Surface and Interface Analysis, 2017, 49, 253-260.	1.8	43
18	Atomic force acoustic microscopy: Influence of the lateral contact stiffness on the elastic measurements. Ultrasonics, 2016, 71, 271-277.	3.9	9

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19	Modeling the limited degree of starch gelatinization. Starch/Staerke, 2016, 68, 727-733.	2.1	9
20	New Data Analysis Tools for X-ray Photoelectron Spectroscopy (XPS) and Spectroscopic Ellipsometry (SE): Uniqueness Plots and Width Functions in XPS, and Distance, Principal Component, and Cluster Analyses in SE. Microscopy and Microanalysis, 2016, 22, 344-345.	0.4	0
21	Uniqueness plots: A simple graphical tool for identifying poor peak fits in X-ray photoelectron spectroscopy. Applied Surface Science, 2016, 387, 155-162.	6.1	51
22	Formation of Si1+ in the early stages of the oxidation of the Si[001] 2 × 1 surface. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2016, 34, .	2.1	5
23	Accurate peak fitting and subsequent quantitative composition analysis of the spectrum of Co $2 < i > p < /i >$ obtained with Al Kα radiation: I: cobalt spinel. Surface and Interface Analysis, 2016, 48, 252-256.	1.8	105
24	Aperture-time of oxygen-precursor for minimum silicon incorporation into the interface-layer in atomic layer deposition-grown HfO2/Si nanofilms. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2015, 33, .	2.1	7
25	Solventless synthesis of ruthenium nanoparticles. Applied Surface Science, 2015, 340, 25-34.	6.1	29
26	Elastic heterogeneities at the nanoscale in DLC films grown by PLD. Materials Research Express, 2015, 2, 025009.	1.6	12
27	Indium and gallium diffusion through zirconia in the TiN/ZrO2/InGaAs stack. Applied Physics Letters, 2015, 106, .	3.3	12
28	As4 overpressure effects on the phase purity of cubic GaN layers grown on GaAs substrates by RF-MBE. Applied Surface Science, 2015, 353, 588-593.	6.1	15
29	Controlling the Optical, Electrical and Chemical Properties of Carbon Inverse Opal by Nitrogen Doping. Advanced Functional Materials, 2014, 24, 2612-2619.	14.9	22
30	Porous Materials: Controlling the Optical, Electrical and Chemical Properties of Carbon Inverse Opal by Nitrogen Doping (Adv. Funct. Mater. 18/2014). Advanced Functional Materials, 2014, 24, 2611-2611.	14.9	1
31	Practical methods for background subtraction in photoemission spectra. Surface and Interface Analysis, 2014, 46, 897-905.	1.8	128
32	Characterization of lead zirconate titanate (53/47) films fabricated by a simplified sol–gel acetic-acid route. Journal of Materials Science: Materials in Electronics, 2013, 24, 1981-1988.	2.2	4
33	Physical and electrical characteristics of atomic-layer deposition-HfO2 films deposited on Si substrates having different silanol Si-OH densities. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2013, 31, .	2.1	6
34	Interface layer in hafnia/Si films as a function of ALD cycles. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2013, 31, .	2.1	12
35	Study of the pseudo- $(1\tilde{A}-1)$ surface by RHEED and XPS for InGaN/GaN (0001)/Al2O3 heterostructures grown by PA-MBE. Journal of Crystal Growth, 2013, 378, 295-298.	1.5	10
36	The slope-background for the near-peak regimen of photoemission spectra. Journal of Electron Spectroscopy and Related Phenomena, 2013, 189, 76-80.	1.7	48

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37	Photocatalytic degradation of 2,4-dichlorophenoxyacetic acid under visible light: Effect of synthesis route. Materials Chemistry and Physics, 2013, 139, 423-430.	4.0	38
38	Diffusion of In and Ga in TiN/HfO2/InGaAs nanofilms. Journal of Applied Physics, 2013, 114, .	2.5	20
39	Characterization of geometrical factors for quantitative angle-resolved photoelectron spectroscopy. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2012, 30, 040605.	2.1	3
40	Following the Integration of Diamond Particles on the Lapping-Plate Surface: Towards a More Efficient Charging Process. Journal of Tribology, 2012, 134, .	1.9	3
41	Chitosan Supported onto Agave Fiber—Postconsumer HDPE Composites for Cr(VI) Adsorption. Industrial & Engineering Chemistry Research, 2012, 51, 5939-5946.	3.7	28
42	Resolving overlapping peaks in ARXPS data: The effect of noise and fitting method. Journal of Electron Spectroscopy and Related Phenomena, 2012, 184, 533-541.	1.7	42
43	Self-Assembly of Î ² GaN/MgO Nanobars. Advanced Science Letters, 2012, 16, 229-236.	0.2	O
44	Instrument-related geometrical factors affecting the intensity in XPS and ARXPS experiments. Journal of Electron Spectroscopy and Related Phenomena, 2011, 184, 487-500.	1.7	35
45	Structure of Ultra-Thin Diamond-Like Carbon Films Grown with Filtered Cathodic Arc on Si(001). Analytical Sciences, 2010, 26, 267-272.	1.6	21
46	Postconsumer highâ€density polyethylene/agave fiber foamed composites coated with chitosan for the removal of heavy metals. Journal of Applied Polymer Science, 2010, 115, 2971-2980.	2.6	5
47	Effect of monochromator X-ray Bragg reflection on photoelectric cross section. Journal of Electron Spectroscopy and Related Phenomena, 2010, 182, 81-83.	1.7	31
48	Thermal stability of nitrogen in nitrided HfSiO2/SiO2/Si(001) ultrathin films. Journal of Applied Physics, 2008, 104, .	2.5	23
49	Aggregate Formation and Segregation of Maize Starch Granules Cooked at Reduced Moisture Conditions. Starch/Staerke, 2005, 57, 301-309.	2.1	17
50	Elastic Anomaly for SrTiO3 Thin Films Grown on Si(001). Microscopy and Microanalysis, 2004, 10, 826-827.	0.4	0
51	Identification of bound water through infrared spectroscopy in methylcellulose. Journal of Food Engineering, 2003, 59, 79-84.	5.2	70
52	Theoretical determination of first adsorbed layer of water in methylcellulose. Journal of Food Engineering, 2003, 59, 45-50.	5,2	6
53	Chemical depth profile of ultrathin nitrided SiO2 films. Applied Physics Letters, 2002, 81, 1014-1016.	3.3	65
54	Aggregation in cooked maize starch. Carbohydrate Polymers, 2002, 50, 387-392.	10.2	10

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55	Analysis of the water bound to a polymer matrix by infrared spectroscopy. Journal of Applied Physics, 2001, 89, 5431-5437.	2.5	42
56	Photoemission from the Sr/Si(001) interface. Journal of Applied Physics, 2001, 90, 6070-6072.	2.5	41
57	Geometrical structure of the 12 â^'ML (2 Ã — 1) and 13 â^'ML (2 Ã — 3) Ba/Si (001) interfaces. Physical Review B, 2000, 61 12988-12991.	l, 3.2	36
58	Lattice compression of Si crystals and crystallographic position of As impurities measured with x-ray standing wave spectroscopy. Journal of Applied Physics, 1999, 85, 1429-1437.	2.5	15
59	Can studies of the II-VIs profit from the use of synchrotron radiation and the DOE financial support thereof?. Journal of Electronic Materials, 1999, 28, 804-809.	2.2	0
60	Calculated electron energy distribution of negative electron affinity cathodes. Surface Science, 1999, 436, 83-90.	1.9	33
61	Electron transverse energy distribution in GaAs negative electron affinity cathodes: Calculations compared to experiments. Journal of Applied Physics, 1996, 80, 1809-1815.	2.5	23
62	Evolution of the crystallographic position of As impurities in heavily doped Si crystals as their electrical activity changes. Applied Physics Letters, 1996, 68, 3090-3092.	3. 3	23
63	Physics of highâ€intensity nanosecond electron source: Charge limit phenomenon in GaAs photocathodes. Journal of Applied Physics, 1996, 79, 7318-7323.	2.5	32
64	Large-angle bond-rotation relaxation for CdTe(110). Physical Review B, 1995, 51, 10774-10778.	3.2	13
65	ThresholdK-LLAuger spectra of P in InP. Physical Review A, 1994, 50, 1359-1371.	2.5	32
66	In/Si(111)-â^š3 \tilde{A} — â^š3 interface: An unrelaxedT4geometry. Physical Review Letters, 1993, 71, 1204-1207.	7.8	34
67	Electronic structure and Schottky-barrier formation on GaAs (100) surfaces prepared by thermal desorption of a protective arsenic coating. Physical Review B, 1992, 45, 11108-11119.	3.2	33
68	Effects of annealing InP(110) surfaces on Schottky barrier heights at Pd/InP(110) interfaces. Journal of Applied Physics, 1992, 71, 314-317.	2.5	6
69	X-ray standing-wave study of monolayers of Sb on GaAs(110). Physical Review B, 1992, 46, 7276-7279.	3.2	31
70	Photoemission study of interfacial chemistry at metal-InP(110) interfaces with Sb interlayers. Physical Review B, 1992, 45, 13531-13537.	3.2	1
71	Thermal stability of Schottky barriers at Au and Ag/InP(110) interfaces with Sb interlayers. Applied Physics Letters, 1991, 59, 3121-3123.	3.3	7
72	Effect of annealing Sb/InP(110) interfaces and Schottky barrier formation of Ag on annealed Sb/InP(110) surfaces. Applied Physics Letters, 1991, 58, 2243-2245.	3.3	21

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73	Annealing out of Thermal Process-Induced Defects at InP(110) Surfaces-A Novel Method. Japanese Journal of Applied Physics, 1991, 30, L1982-L1984.	1.5	4